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XA-9387 11-20-0



PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Hitoshi TAKEUCHI

Appln. No.: 09/714,183

Group Art Unit: 2877

Filed: November 17, 2000

For: ABERRATION MEASURING APPARATUS, ABERRATION MEASURING
METHOD, PROJECTION EXPOSURE APPARATUS HAVING THE SAME
MEASURING APPARATUS, DEVICE MANUFACTURING METHOD USING
THE SAME MEASURING METHOD, AND EXPOSURE METHOD

* * *

THIRD SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT
AND STATEMENT UNDER 37 C.F.R. § 1.97(e)

Commissioner for Patents
Washington, D.C. 20231

Sir:

Supplementing the Information Disclosure Statement
dated May 29, 2002, and without any assertion as to
materiality or prior art effect, the documents listed on
the attached Form PTO-1449 are hereby cited.

The documents on the attached List were recently cited
in a European Search Report.

The Commissioner is hereby authorized to charge to
Deposit Account No. 50-1165 any fees under 37 C.F.R. §§
1.16 and 1.17 that may be required by this paper, and to
credit any overpayment to that Account.

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STATEMENT UNDER 37 C.F.R. § 1.97(e)

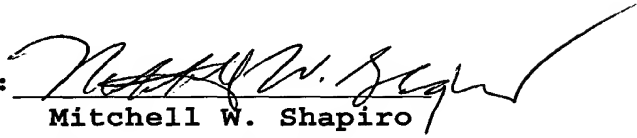
The undersigned hereby states that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Statement.

Respectfully submitted,

MWS:sjk

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By:


Mitchell W. Shapiro
Reg. No. 31,568

November 14, 2002



FORM PTO-1449

Atty. Docket No.

Appln. No.

LIST OF DOCUMENTS CITED BY APPLICANT

XA-9387

09/714,183

Applicant

Hitoshi TAKEUCHI et al.

Filing Date

November 17, 2000

Group

2877

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date
	AA	5,202,748	04/13/93	MacDonald et al.	356	360	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Country	Class	Sub-class	Translation
	AL						
	AM						
	AN						
	AO						
	AP						
	AQ						

OTHER (including author, title, date, pertinent pages, etc.)

AR Gourlay et al., "A real-time closed-loop liquid crystal adaptive optics system: first results", Optics Communications, Vol. 137, No. 1-3, April 15, 1997, pp. 17-21.

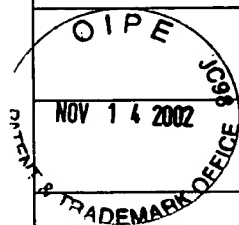
AS

AT

Examiner

Date Considered

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.



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